



PATENT  
Customer No. 22,852  
Attorney Docket No. 02887.0212

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Yuichiro YAMAZAKI, et al.

Application No.: 10/026,727

Filed: December 27, 2001

For: SUBSTRATE INSPECTION  
SYSTEM AND METHOD FOR  
CONTROLLING SAME

)  
)  
) Group Art Unit: 2881

)  
) Examiner: EL SHAMMAA, Mary A.  
)  
)  
)  
)  
)  
)

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

AMENDMENT

In reply to the Office Action of February 18, 2003, with a period for response extending through June 18, 2003, by the attached Petition for Extension of Time and requisite fee payment, please amend the application as follows. Applicants also respectfully request the Examiner's reconsideration in view of the following remarks:

IN THE DRAWINGS:

Filed herewith is a paper entitled "Submission of Corrected Formal Drawing," in which Examiner-required changes to Fig. 3 were made.

IN THE ABSTRACT:

Please replace the current Abstract with the Substitute Abstract attached on a separate page. The full text of the Abstract in clean form is as follows:

FINNEGAN  
HENDERSON  
FARABOW  
GARRETT &  
DUNNER LLP

1300 I Street, NW  
Washington, DC 20005  
202.408.4000  
Fax 202.408.4400  
www.finnegan.com

RECEIVED  
JUN 19 2003  
TECHNOLOGY CENTER 28000  
6-24-03